

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination DIERICKX ET AL.	
		Examiner Deborah Yee	Art Unit 1742	Page 1 of 1

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*	B	US-R28,523	08-1975	Hill et al.	420/8
	C	US-			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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